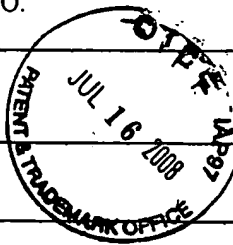


FORM PTO-1449 (Modified)				ATTY. DOCKET NO. P27955		SERIAL NO. 10/538,763	
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT				APPLICANT: Steven D. SLONAKER et al.			
(Use several sheets if necessary)				FILING DATE: June 10, 2005		GROUP: 2812	



REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS					
EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)		
		Nakashima, T., "Impact of Zernike cross-term on linewidth control", SPIE Vol. 4691, 2002, July 15, 2002, pages 33-43
		Shiode, Y., "Method of Zernike coefficients extraction for optics aberration", SPIE Vol. 4691, 2002, pages 1453-1464, Abstract (pages 1453), 2.2 Illumination source Design (pages 1454-1455)
		Nakashima, T., "Evaluation of Zernike sensitivity method for CD distribution", SPIE Vol. 5040, 2003, pages 1600-1610
		Slonaker, S., "Further pursuit of correlation between lens aberration content and imaging performance", SPIE Vol. 4346, 2001, pages 1394-1403
		International Search Report (PCT/ISA/210) for International Application No. PCT/US04/04854

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.